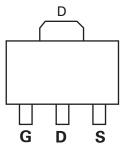


### 2SJ288-VB Datasheet

## P-Channel 60-V (D-S) MOSFET

PRODUCT SUMMARY							
V <sub>DS</sub> (V)	R <sub>DS(on)</sub> (Ω)	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (Typ.)				
- 60	0.058 at V <sub>GS</sub> = - 10 V	- 6.5	30 nC				
- 60	0.065 at V <sub>GS</sub> = - 4.5 V	- 5.5	30 110				



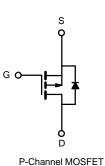
#### FEATURES

- TrenchFET<sup>®</sup> Power MOSFET
- 100 % UIS Tested

#### **APPLICATIONS**

Load Switch





ABSOLUTE MAXIMUM RATINGS	<b>S</b> (T <sub>A</sub> = 25 °C, unle	ess otherwise no	ted)	
Parameter		Symbol	Limit	Unit
Drain-Source Voltage	V <sub>DS</sub>	- 60	V	
Gate-Source Voltage	V <sub>GS</sub>	± 20	v	
	T <sub>C</sub> = 25 °C		- 6.5 <sup>a</sup>	
Continuous Drain Current (T <sub>1</sub> = 150 °C)	T <sub>C</sub> = 70 °C	1-	- 5.2	
Continuous Drain Current (1) = 150°C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	- 4.8 <sup>b</sup>	A
	T <sub>A</sub> = 70 °C		- 4.1 <sup>b</sup>	
Pulsed Drain Current		I <sub>DM</sub>	- 20	
Avalanche Current Pulse	L = 0.1 mH	I <sub>AS</sub>	- 4.5	
Single Pulse Avalanche Energy	L = 0.1 mm	E <sub>AS</sub>	10.1	mJ
Continuous Source-Drain Diode Current	T <sub>C</sub> = 25 °C	L.	6.9 <sup>a</sup>	A
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	3.5 <sup>b</sup>	
	T <sub>C</sub> = 25 °C		10.4 <sup>a</sup>	
Manimum Davian Dissingtion	T <sub>C</sub> = 70 °C		6.6 <sup>a</sup>	10/
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	2.1 <sup>b</sup>	W
	T <sub>A</sub> = 70 °C		1.1 <sup>b</sup>	7
Operating Junction and Storage Temperature Ra	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient <sup>b</sup>	Steady State	R <sub>thJA</sub>	33	40	°C/W		
Maximum Junction-to-Case	Steady State	R <sub>thJC</sub>	0.98	1.2	0/00		

Notes:

a. Based on  $T_C = 25 \ ^{\circ}C$ .

b. Surface mounted on 1" x 1" FR4 board.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static			·	<u> </u>	·	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 V, I_D = -250 \mu A$	- 60			V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = - 250 μA		68		mV/°C
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	$I_D = -250 \mu A$		- 5.2		mv/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = -250 \ \mu A$	- 1.2		- 2.5	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA
Zara Cata Valtaga Drain Current		$V_{DS} = -60 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			- 1	μA
Zero Gate Voltage Drain Current	IDSS	$V_{DS}$ = - 60 V, $V_{GS}$ = 0 V, $T_{J}$ = 55 °C			- 10	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	V <sub>DS</sub> = - 5 V, V <sub>GS</sub> = - 10 V	- 25			А
	Р	V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 3 A		0.058		Ω
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	$V_{GS} = -4.5 \text{ V}, \text{ I}_{D} = -2 \text{ A}$		0.065		
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = - 15 V, I <sub>D</sub> = - 5 A	20			S
Dynamic <sup>b</sup>				•		
Input Capacitance	C <sub>iss</sub>			1500		pF
Output Capacitance	C <sub>oss</sub>	$V_{DS}$ = - 25 V, $V_{GS}$ = 0 V, f = 1 MHz		200		
Reverse Transfer Capacitance	C <sub>rss</sub>			150		
Total Gate Charge	0	$V_{DS} = -30 \text{ V}, \text{ V}_{GS} = -10 \text{ V}, \text{ I}_{D} = -5 \text{ A}$		38	56	nC
Iotal Gate Charge	Qg			19	30	
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS}$ = - 30 V, $V_{GS}$ = - 4.5 V, $I_D$ = - 5 A		9		
Gate-Drain Charge	Q <sub>gd</sub>			10		
Gate Resistance	Rg	f = 1 MHz	5.2			Ω
Turn-On Delay Time	t <sub>d(on)</sub>			10	15	
Rise Time	t <sub>r</sub>	$V_{DD}$ = - 2 V, $R_L$ = 2 $\Omega$		7	15	- ns
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong$ - 5 A, $V_{GEN}$ = - 10 V, $R_g$ = 1 $\Omega$		70	110	
Fall Time	t <sub>f</sub>			40	60	
Drain-Source Body Diode Characteristic	s					
Continuous Source-Drain Diode Current	۱ <sub>S</sub>	T <sub>C</sub> = 25 °C			- 6.9	A
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>				- 15	
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = - 3 A		- 1	- 1.5	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>			45	68	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	$L = 5.4  di/dt = 10.4/m = 7.5  ^{\circ}$		59	120	nC
Reverse Recovery Fall Time	t <sub>a</sub>	I <sub>F</sub> = - 5 A, di/dt = 10 A/μs, T <sub>J</sub> = 25 °C		29		
Reverse Recovery Rise Time	t <sub>b</sub>			16		ns

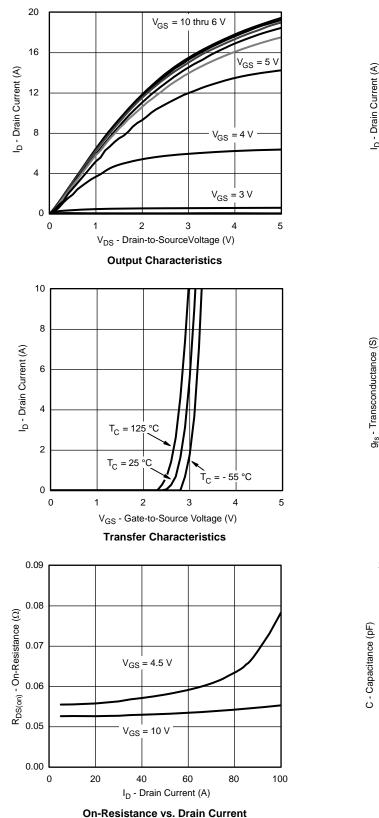
Notes:

a. Pulse test; pulse width  $\leq$  300  $\mu s,$  duty cycle  $\leq$  2 %.

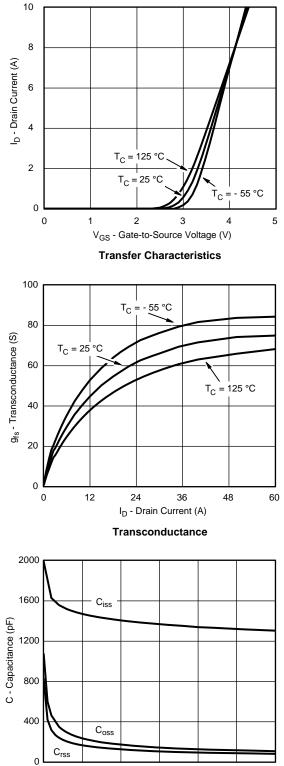
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



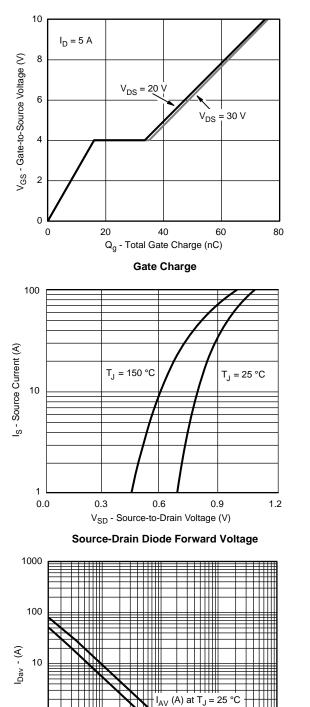


#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



V<sub>DS</sub> - Drain-to-Source Voltage (V) Capacitance





#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

T<sub>in</sub> - (s) Single Pulse Avalanche Current Capability vs. Time

0.01

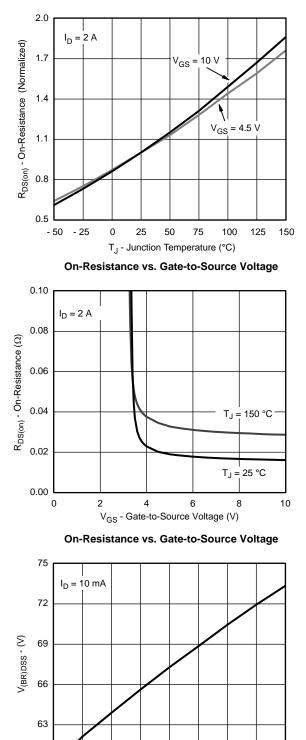
0.1

1

11111

 $I_{AV}$  (A) at  $T_{J}$  = 150

0.001



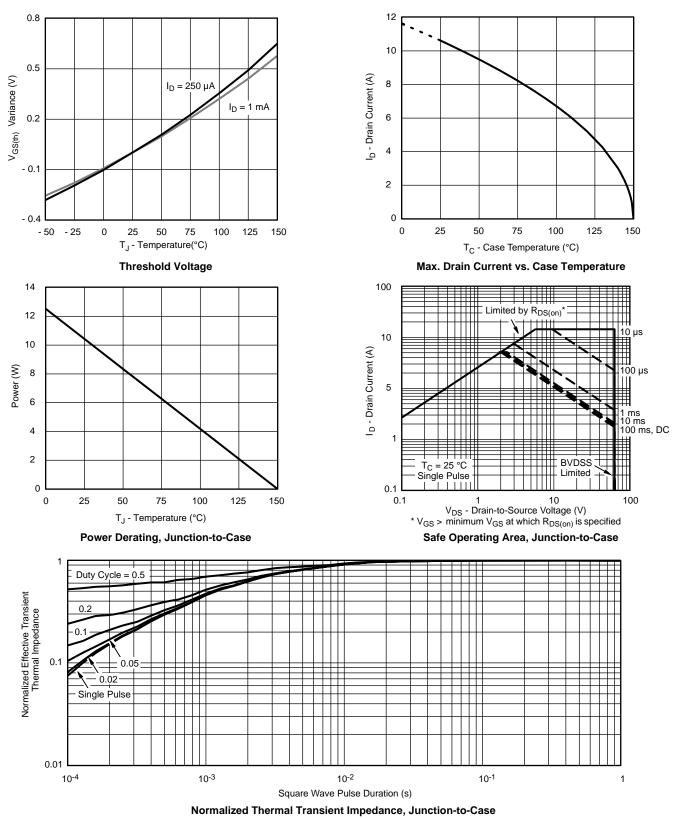
Drain-Source Breakdown Voltage vs. Junction Temperature

1

0.1

0.0001

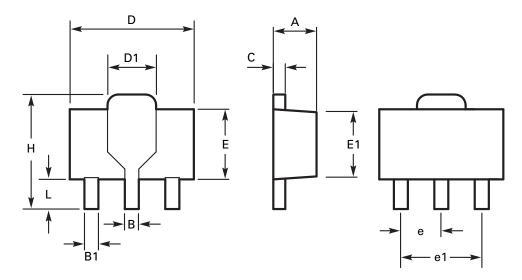




#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



Package outline - SOT89



DIM	Millimeters		Inc	Inches DIM		Millimeters		Inc	hes
	Min	Max	Min	Max		Min	Max	Min	Max
А	1.40	1.60	0.550	0.630	E	2.29	2.60	0.090	0.102
В	0.44	0.56	0.017	0.022	E1	2.13	2.29	0.084	0.090
B1	0.36	0.48	0.014	0.019	е	1.50 BSC		0.059 BSC	
С	0.35	0.44	0.014	0.017	e1	3.00 BSC		0.118	BSC
D	4.40	4.60	0.173	0.181	Н	3.94	4.25	0.155	0.167
D1	1.62	1.83	0.064	0.072	L	0.89	1.20	0.035	0.047

Note: Controlling dimensions are in millimeters. Approximate dimensions are provided in inches



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